

Ultra SharpView

PCB Production Solutions

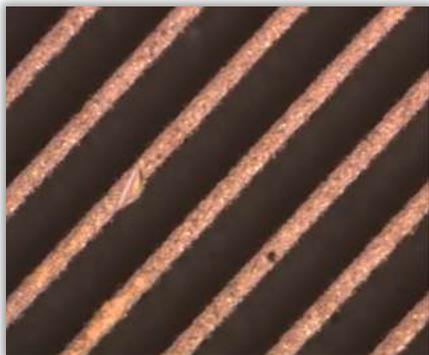
Ultra SharpView is a specially designed verification station for the most advanced IC substrate production of FC-BGA. The system's ability to verify fine line PCBs down to 5 micron line and space guarantees that manufacturers have long term support for current and future needs. Ultra SharpView's high magnification is further enhanced with Amethyst Technology™ to avoid microscopic defect escapes during the verification process.



Ultra SharpView introduces the use of a microscope objective for the challenging task of microscopic defect verification. When scanning FC-BGA IC substrates with line widths of below 10 microns, achieving a clear image of defects as small as 1.5 microns is a must. Ultra SharpView enables fast and accurate verification with no real defect escapes in order to meet these requirements.

Versatile illumination sources of bright field, dark field, grazing and UV light provide the optimal clear images needed to avoid escapes of any fine short, open or nick on any shiny or low contrast surface.

Sharp and Clear defect image on 9 μ m line



Ultra SharView Specifications:

Min L/S [μm]	5/5
Min defect size [μm]	1.2
Auto focus	Yes
Vibrations	No
Magnification	220x-5000x
Field of View	1.2mm – 0.19mm
White Illumination	3 independently controlled Illumination types (LED-based): coaxial, diffusive, grazing
UV Illumination	Controllable UV illumination
Image processing	Yes
Average time between defects [s]	0.7
Defect in center 3 rd of image	Yes
Dynamic zoom	Yes
UV Illumination	Yes
Image Display	23"
Operating system	Linux
AOI Systems Supported	Orbotech Ultra Fusion™ series

Specifications are subject to change without notice